



Fig. 1- Real Time Antenna Measurement

- Cellular, M2M
- CAT and NB1
- GSM,WCDMA,LTE
- RFID, GPS, Wi-Fi, BT
- CP Antenna Test
- Sample Lot Testing
- Stand Alone Antenna
- Base Station Antenna
- Phase Array Antenna

- OTA Production Testing
- Rapid OTA Phantom Kit
- Smart Antennas (MIMO)
- IoT Antenna Performance
- Embedded Antenna Design
- Antenna Design and Test Lab
- Antenna Pattern Measurement
- Anechoic Chamber Alternative

Features and Functions

- 300 MHz 6 GHz
- 1,600 H-field probes
- Far-field resolution: 1.8° for theta and 3.6° for phi
- Test CP (circularly polarized) antennas.
- Analyze your embedded Antenna and wireless device.
- Iteratively test and optimize embedded antenna design.
- Perform highly repeatable and rapid over-the air wireless device measurements.
- Get repeatable & reliable results that pinpoint the cause of a design failure
- Verify final product performance in real time.
- Gain immediate insight into the root causes of performance issues analyzing the near-field results.



Fig. 2- Real Time EMC and EMI Testing

- Filtering
- Shielding
- Immunity
- Signal Integrity
- Common Mode
- Broadband Noise
- IC Level EMC Test
- NFC Antenna Testing

- Current Distribution
- Emissions Along Traces
- Good Board vs. Bad Board
- Material Properties Scanning
- Absorber effectiveness Testing
- High Resolution EMC Scanner
- Manufacturing Problem Solving
- Self-interference /desense problems

Features and Functions

- 150 kHz 8 GHz
- 1,218 H-field probes
- Analyze High Speed / High Power PCB Design
- Analyze High Speed / High Density PCB Design
- Visualize the root cause of Design Failure even when the problem is intermittent.
- Pinpoint the cause of design failure even when the problem
- Zoom into the problem area after locating the unintended radiators in seconds
- Get repeatable & reliable results that pinpoint the cause of a design failure
- Address EMC & signal integrity concerns in the design of ultra-high speed (>2 GHz) PCBs



Fig. 3 – TRP and OTA Measurement

- TRP: Absolute radiated power measurement with a 2-sigma accuracy of +/- 1.6 dB or relative *PASS/FAIL* radiated power comparison with a +/-0.5 dB accuracy.
- Pattern: Rapid *PASS/FAIL* pattern comparison; important for devices designed with beam forming or other adaptive capabilities.
- Dynamic effects: Detuning due to body parts can be evaluated in a production line with a phantom kit
- Tuneable Antennas: Very fast frequency by frequency measurement capabilities helps you verify the antennas are tuning to the frequency as expected.

Features and Functions

- Tests in compliant CTIA chambers have shown that results from a half + head and a full head show good correlation. A +/- 2 dB accuracy with two rotated half-head measurements compared to a CTIA chamber should be possible, given typical OTA measurement uncertainties.
- Far-Field Applications includes:
 - a. Predict the Open Area Test Site (OATS) or Semi Anechoic Chamber (SAC) radiated EMI levels of a printed circuit board (PCB).
 - b. Far-Field application supports 30 MHz 1 GHz regulatory compliance limits Class A or Class B FCC, CISPR and Industry Canada, 10m, 3m and 1m test distances

www.emscanlab.com

info@emscanlab.com

1-786-205-7022